

# imiD 2017

August 28 - 31, 2017 / BEXCO, Busan, Korea

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<b>Session Title:</b>	<b>39. Photometry and Measurement</b>
<b>Date:</b>	Aug. 30, 2017 (Wednesday)
<b>Time:</b>	14:00-15:30
<b>Room</b>	G (Room 108)
<b>Session Chairs</b>	Prof. Jae-Hyeon Ko (Hallym Univ., Korea) Prof. Dong-Sing Wu (Nat'l Chung Hsing Univ., Taiwan)

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[G39-1]

14:00-14:25

**[Invited] Photometry of LED and OLED Devices**

Tony Bergen (Photometric Solutions Int'l Pty Ltd., Australia)

[G39-2]

14:25-14:50

**[Invited] Photometry Measurement for Curved Surface Sources**

Hsueh-Ling Yu (Singularity Optics Corp., Taiwan), Richard Young (Instrument Systems GmbH, Germany), Chin-Chai Hsiao, and Wen-Chun Liu (Center for Measurement Standards, Taiwan)

[G39-3]

14:50-15:15

**[Invited] Psychophysical Approach for Evaluating Performance of OLED Panels for Lighting**

Yasuki Yamauchi (Yamagata Univ., Japan)

[G39-4]

15:15-15:30

**The Design of Optimized Pattern on Light Guide Plate with a Curve of 20R**

Sungrae Lee, Hee Cheol Kim, Yong Hun Jeong, Byuong Ku Kim, and Seung Jun Han (LG Display Co., Ltd., Korea)